Notice of References Cited Application/Control No. 09/523,990 Examiner DANIEL WALSH Applicant(s)/Patent Under Reexamination LIN ET AL. Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,534,804 A	08-1985	Cade, Paul E.	438/694
*	В	US-5,075,201 A	12-1991	Koh, Wei H.	430/321
*	C	US-5,128,283 A	07-1992	Tanaka, Koukiti	438/703
*	D	US-5,314,837 A	05-1994	Barber et al.	438/504
*	Е	US-5,401,691 A	03-1995	Caldwell, Roger F.	438/633
*	F	US-5,547,906 A	08-1996	Badehi, Pierre	438/109
*	G	US-5,581,122 A	12-1996	Chao et al.	257/691
*	Ι	US-5,644,102 A	07-1997	Rostoker, Michael D.	174/547
*	I	US-6,014,318 A	01-2000	Takeda, Shinji	361/764
*	J	US-6,081,040 A	06-2000	Okuda et al.	257/797
*	K	US-6,181,017 B1	01-2001	Hatchard et al.	257/797
*	L	US-6,239,031 B1	05-2001	Kepler et al.	438/692
*	М	US-6,278,193 B1	08-2001	Coico et al.	257/797

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	х						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 09/523,990 Examiner DANIEL WALSH Applicant(s)/Patent Under Reexamination LIN ET AL. Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2001/0045011 A1	11-2001	Ross et al.	29/852
*	В	US-2002/0003293 A1	01-2002	Kobayashi, Yutaka	257/676
*	C	US-6,352,204 B1	03-2002	Hattersley et al.	235/472.01
*	D	US-2002/0052056 A1	05-2002	Minamio et al.	438/25
*	Е	US-6,395,580 B1	05-2002	Tseng, Fouriers	438/108
*	F	US-6,420,790 B1	07-2002	Koizumi, Tsutomu	257/787
*	G	US-2002/0106833 A1	08-2002	Kobayashi, Yutaka	438/108
*	Ι	US-6,476,499 B1	11-2002	Hikita et al.	257/777
*	-	US-2003/0072926 A1	04-2003	Grigg et al.	428/195.1
*	J	US-6,593,168 B1	07-2003	Ehrichs et al.	438/108
*	K	US-2003/0209787 A1	11-2003	Kondo et al.	257/673
*	L	US-2005/0022379 A1	02-2005	Rumsey et al.	029/842
*	М	US-2006/0283961 A1	12-2006	Misawa et al.	235/492

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Ø					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	\ \	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 09/523,990	Applicant(s)/Patent Under Reexamination LIN ET AL.		
Notice of Hererences Office	Examiner	Art Unit		
	DANIEL WALSH	2887	Page 3 of 3	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,436,077 B2	10-2008	Hasegawa, Kiyoshi	257/797
*	В	US-2009/0051027 A1	02-2009	Lin, Mou-Shiung	257/734
	O	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Η	US-			
	ı	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Ρ					
	œ					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	ح	
	>	
	8	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.